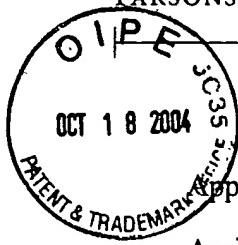


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Applicants: Wayne Chen et al.  
Assignee: KLA-Tencor Corporation  
Title: System and Methods for Classifying Anomalies of Sample Surfaces  
Application No.: 10/613,634 Filing Date: July 3, 2003  
Examiner: Michael Patrick Stafira Group Art Unit: 2877  
Docket No.: TNCR.178US1 Conf. No.: 4612

Mail Stop Amendment  
Commissioner For Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Transmitted herewith are the following documents in the above-identified application:

- (1) Return receipt postcard;
- (2) This Transmittal Letter (1 page);
- (3) Information Disclosure Statement (2 pages);
- (4) PTO Form 1449 (1 sheet);
- (5) 3 Cited References; and
- (6) Check for \$180.00.

- |                                     |  |               |                      |
|-------------------------------------|--|---------------|----------------------|
| <input checked="" type="checkbox"/> | Fee for Submission of Information Disclosure Statement   | \$            | 180.00               |
|                                     |  | <b>Total:</b> | <b><u>180.00</u></b> |
| <input checked="" type="checkbox"/> | Conditional Petition for Extension of Time: If an extension of time is required for timely filing of the enclosed document(s) after all papers filed with this transmittal have been considered, an extension of time is hereby requested. |               |                      |
| <input checked="" type="checkbox"/> | Please charge any additional fees required and credit any overpayment to our Deposit Account No. 502664.   |               |                      |

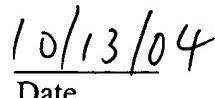
Certificate of Mailing Under 37 CFR 1.8

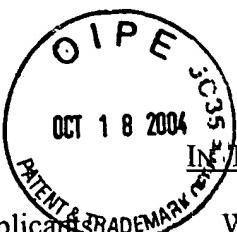
I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope address to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on October 13, 2004.

Franklin Dyer

Respectfully submitted,

  
James S. Hsue  
Reg. No. 29,545

  
10/13/04  
Date



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Wayne Chen et al.

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Commissioner for Patents  
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Alexandria, VA 22313-1450

**INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant(s) call(s) the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

This application has a filing date after June 30, 2003. Copies of the U.S. Patent(s) and U.S. Published Patent Application(s) documents listed on the accompanying Form PTO-1449 are not enclosed.

Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a representation that a search has been made (other than as indicated by any cited document), or (3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

This information disclosure statement is submitted under 37 C.F.R. § 1.97(c). A check including \$180.00 for the information disclosure statement fee under 37 C.F.R. § 1.17(p), is

Attorney Docket No.: TNCR.178US1

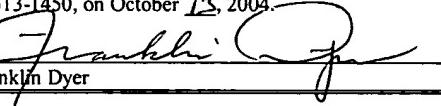
Application No.: 10/613,634

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enclosed. The Commissioner is authorized, however, to charge any fee that may be required, or to credit any overpayment, against Deposit Account No. 502664. This form is being submitted in duplicate.

Certificate of Mailing Under 37 CFR 1.8

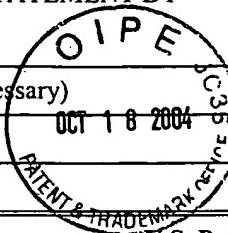
I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope address to:  
Commissioner for Patents, P.O. Box 1450, Alexandria, VA  
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Franklin Dyer

Respectfully submitted,

  
James S. Hsue  
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10/13/04  
Date

U.S. Department of Commerce, Patent and Trademark		Atty. Docket No.	Application No.
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		TNCR.178US1	10/613,634
(Use several sheets if necessary)		Applicant(s)	Conf. No.
		Wayne Chen et al.	4612
		Filing Date	Group
		July 3, 2003	2877

**U.S. Patent Documents**

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
1	5,699,447	Dec., 1997	Alumot et al.			
2	5,864,394	Jan., 1999	Jordan, III et al.			
3	5,907,628	May, 1999	Yolles et al.			
4	5,991,699	Nov., 1999	Kulkarni et al.			
5	6,201,601	Mar., 2001	Vaez-Iravani, et al.			

**U.S. Published Patent Application Documents**

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate

**Foreign Patent Documents**

Translation

		Document	Date	Country	Class	Subclass	Yes	No

**OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)**

6	"Acoustic Scanners and Modulators," M. Gottlieb, Optical Scanning, ed. by Gerald F. Marshall, Dekker 1991, pp. 615-685.
7	"CMP Applications for Sub-0.25.mu.m Process Technologies," D. Pramanik et al., presented at Electrochemical Society Proceedings: Chemical Mechanical Planarization in IC Device Manufacturing (2.sup.nd International Symposium), vol. 98-7, 1998.
8	"Integrated CMP Defect Monitoring Strategy," W. Chen et al., presented at The Electrochemical Society Proceedings: Chemical Mechanical Polishing in IC Device Manufacturing III, Editors: V.A. Arimoto et al., PV99-37, Honolulu, Oct. 1999.

Examiner Date Considered

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.